Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10520151	KURITA, TADASHI
Examiner	Art Unit

2621

SEARCHED				
Class	Subclass	Date	Examiner	
386	46,65,66,95,98,102,109	3/13/2008	GT	
348	565	2/15/2009	GT	

GELEK TOPGYAL

SEARCH NOTES			
Search Notes	Date	Examiner	
Thai Tran: Determined any subsampling system used for PIP processing meets the claimed invention.	3/13/2008	GT	
Researched	9/12/08	GT	
See attached for Inventor and Interference search. Thai Tran deteremined allowability of claims.	1/17/2009	GT	

INTERFERENCE SEARCH				
Class		Subclass	Date	Examiner
386	46		2/15/2009	GT
348	565		2/15/2009	GT

/GELEK TOPGYAL/ Examiner.Art Unit 2621	

U.S. Patent and Trademark Office Part of Paper No. : 20090216